

Description

The SI2399DS-T1-GE3 uses advanced trench technology to provide excellent $R_{DS(ON)}$, low gate charge and operation with gate voltages as low as 1.8V. This device is suitable for use as a load switch or in PWM applications .It is ESD protested.

D S S G SOT-23

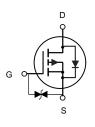
General Features

 $V_{DS} = -20V, I_{D} = -5A$

 $R_{DS(ON)}$ < 40m Ω @ V_{GS} =-4.5V

 $R_{DS(ON)}$ < $60m\Omega$ @ V_{GS} =-2.5V

ESD Rating: 1500V HBM



P-Channel MOSFET

Application

PWM application

Load switch

Package Marking and Ordering Information

Product ID	Pack	Marking	Qty(PCS)
SI2399DS-T1-GE3	SOT-23	3415/AF4E	3000

Absolute Maximum Ratings (T_A=25°C unless otherwise noted)

urce Voltage urce Voltage rrent-Continuous	-20 ±10	V
	±10	V
rrent_Continuous		
none-continuous	-5	A
rrent-Pulsed (Note 1)	-30	A
n Power Dissipation	1.4	W
g Junction and Storage Temperature Range	-55 To 150	$^{\circ}$
Resistance.Junction-to-Ambient (Note 2)	89.3	°C/W
	g Junction and Storage Temperature Range Resistance,Junction-to-Ambient (Note 2)	

P-Channel Enhancement Mode MOSFET

Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit
Off Characteristics						
Drain-Source Breakdown Voltage	BV _{DSS}	V _{GS} =0V I _D =-250μA	-20		-	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} =-20V,V _{GS} =0V	-	-	1	μA
Gate-Body Leakage Current	I _{GSS}	V _{GS} =±10V,V _{DS} =0V	-	-	±10	μA
On Characteristics (Note 3)	Characteristics (Note 3)					
Gate Threshold Voltage	$V_{GS(th)}$	V _{DS} =V _{GS} ,I _D =-250μA	-0.35	-0.55	-0.9	V
Drain-Source On-State Resistance	R _{DS(ON)}	V _{GS} =-4.5V, I _D =-4A	-	30	40	mΩ
Diam-Source On-State Resistance		V _{GS} =-2.5V, I _D =-4A	-	44	60	mΩ
Forward Transconductance	g FS	V _{DS} =-5V,I _D =-4A	8	-	-	S
Dynamic Characteristics (Note4)						
Input Capacitance	C _{lss}	V _{DS} =-10V,V _{GS} =0V,	-	950	-	PF
Output Capacitance	Coss	V _{DS} 10V,V _{GS} -0V, F=1.0MHz	-	165	-	PF
Reverse Transfer Capacitance	C _{rss}	F-1.0WHZ	-	120	-	PF
Switching Characteristics (Note 4)						
Turn-on Delay Time	t _{d(on)}		-	12		nS
Turn-on Rise Time	t _r	V _{DD} =-10V,R _L =2. 5Ω	-	10		nS
Turn-Off Delay Time	t _{d(off)}	V_{GS} =-4.5V, R_{GEN} =3 Ω	_	19		nS
Turn-Off Fall Time	t _f		-	25		nS
Total Gate Charge	Qg	\/ - 40\/ - 40	-	12		nC
Gate-Source Charge	Q_{gs}	V_{DS} =-10V, I_{D} =-4A, V_{GS} =-4.5V	-	1.4	-	nC
Gate-Drain Charge	Q_{gd}	v _{GS} 4.5v	-	3.6	ı	nC
Drain-Source Diode Characteristics						
Diode Forward Voltage (Note 3)	V _{SD}	V _{GS} =0V,I _S =-4A	-	-	-1.2	V
Diode Forward Current (Note 2)	Is		-	-	-4	Α

Notes:

- **1.** Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board, $t \le 10$ sec.
- 3. Pulse Test: Pulse Width ≤ 300µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production



Typical Electrical And Thermal Characteristics

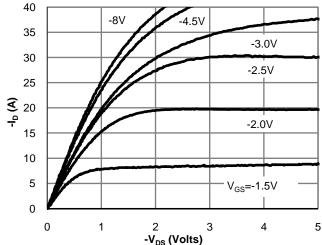


Fig 1: On-Region Characteristics (Note E)

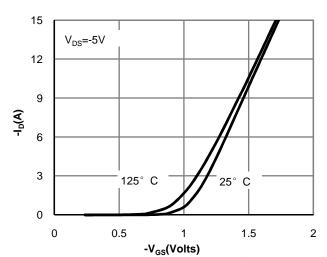


Figure 2: Transfer Characteristics (Note E)

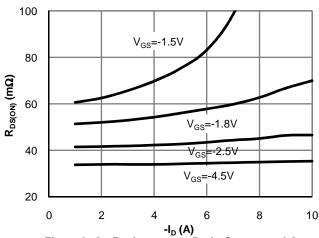


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

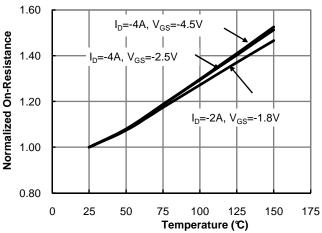


Figure 4: On-Resistance vs. Junction Temperature (Note E)

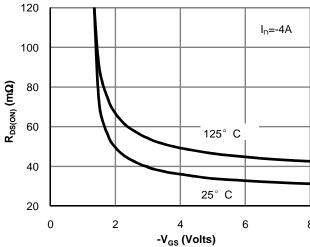


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

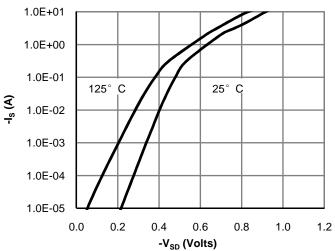
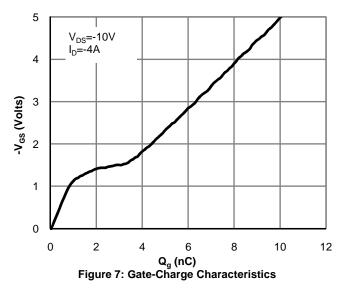
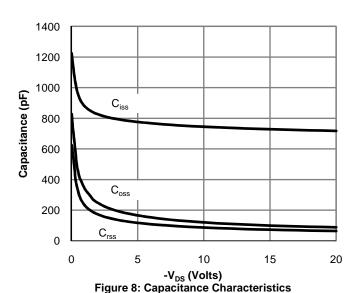
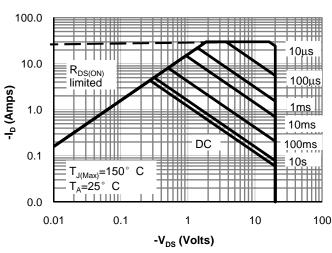


Figure 6: Body-Diode Characteristics (Note E)









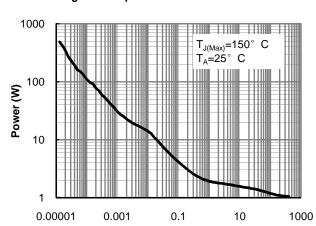


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

Pulse Width (s)
Figure 10: Single Pulse Power Rating Junction-toAmbient (Note F)

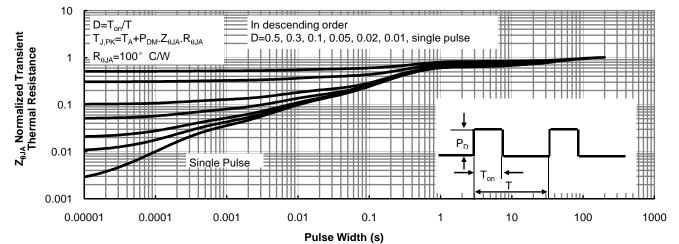
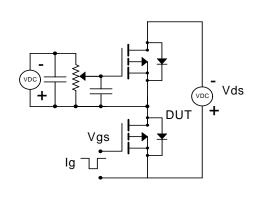
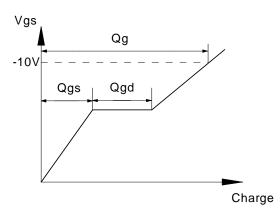


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

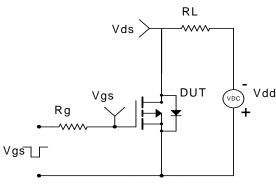
P-Channel Enhancement Mode MOSFET

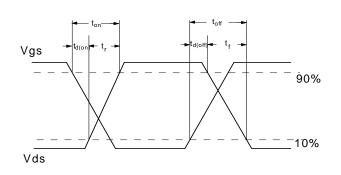
Gate Charge Test Circuit & Waveform



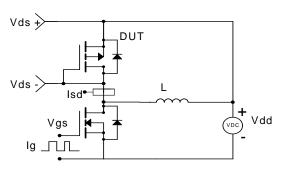


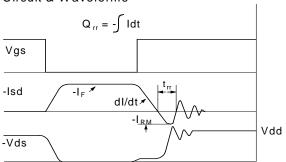
Resistive Switching Test Circuit & Waveforms





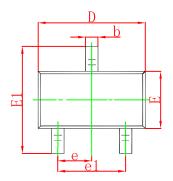
Diode Recovery Test Circuit & Waveforms

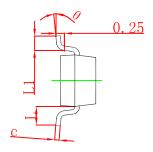


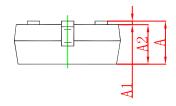




SOT-23 Package Outline Dimensions

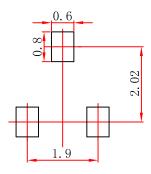






Symbol	Dimensions In Millimeters		Dimensions In Inches		
	Min	Max	Min	Max	
Α	0.900	1.150	0.035	0.045	
A1	0.000	0.100	0.000	0.004	
A2	0.900	1.050	0.035	0.041	
b	0.300	0.500	0.012	0.020	
С	0.080	0.150	0.003	0.006	
D	2.800	3.000	0.110	0.118	
E	1.200	1.400	0.047	0.055	
E1	2.250	2.550	0.089	0.100	
е	0.950 TYP		0.037 TYP		
e1	1.800	2.000	0.071	0.079	
L	0.550 REF		0.022 REF		
L1	0.300	0.500	0.012	0.020	
θ	0°	8°	0°	8°	

SOT-23 Suggested Pad Layout



Note:

- 1. Controlling dimension: in millimeters.
- 2.General tolerance:± 0.05mm.
 3.The pad layout is for reference purposes only.

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